

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/596,022	FURUKAWA ET AL.	
Examiner		Art Unit		Page 1 of 1
YOSEF GEBREYESUS		2811		

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2001/0012658 A1	08-2001	Widmann et al.	438/241
*	B	US-6,333,598 B1	12-2001	Hsu et al.	313/495
*	C	US-2002/0048143 A1	04-2002	Lee et al.	361/502
*	D	US-2002/0151150 A1	10-2002	Bernstein et al.	438/396
*	E	US-2002/0159944 A1	10-2002	Smalley et al.	423/447.6
*	F	US-2003/0096104 A1	05-2003	Tobita et al.	428/332
*	G	US-2003/0132461 A1	07-2003	Roesner et al.	257/213
*	H	US-2003/0211724 A1	11-2003	Haase, Gad S.	438/629
*	I	US-2004/0043629 A1	03-2004	Lee et al.	438/775
*	J	US-2004/0137730 A1	07-2004	Kim et al.	438/689
*	K	US-2005/0062034 A1	03-2005	Dubin, Valery M.	257/020
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.